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Authors

Bichsel, Hans
Tschalaer, Christoph

Publication Date

1968-07-01

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UCRL-17663 Rev. 1

34

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UCRL-17663 Rev. 1
UC-34 Physics
TID-4500 (52nd Ed.)

UNIVERSITY OF CALIFORNIA
Lawrence Radiation Laboratory
Berkeley, California

AEC Contract No. W-7405-eng-48

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A RANGE ENERGY TABLE FOR HEAVY PARTICLES IN SILICON*

Hans Bichsel[†] and Christoph Tschalaer[‡]

Lawrence Radiation Laboratory
University of California
Berkeley, California

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Abstract

Stopping-power S and range R tables for protons, deuterons, tritons, He^3 , He^4 and Li^7 ions of energies between 1- and 200-MeV penetrating silicon absorbers are presented. Auxiliary data include tables for the coefficients C and α needed for the approximate expression $S = C \cdot E^\alpha$ and figures giving the energy dependence for the coefficients of $R = C_R \cdot E^\beta$. A short review is given of principles to be considered in detector applications.

*Work supported in part by the U.S. Atomic Energy Commission and Public Health Service Research Grant No. CA 08150 from the National Cancer Institute.

[†]On leave of absence from the University of Southern California, Los Angeles.

[‡]Now at Rutherford High Energy Laboratory, Didcot, England.

1. Introduction

Since silicon detectors have found wide spread applications, energy-loss tables for heavy particles are a necessity. Recent accurate measurements for protons^{11,33)} permit the presentation of calculated tables with a better basis than previous calculations. In particular it was found that the difference of the I-values of Al and Si is only about 7 eV rather than 12.5 eV as would be expected from a statistical model²⁾. There still are unresolved differences between experimental data²¹⁾ and some changes may have to be made in these tables as further results become available. A number of auxiliary tables and figures useful for the design and evaluation of particle-identifier systems are presented.

2. General Basis for Stopping-Power and Range-Energy Tables

2.1. Theory

The mean energy loss S of energetic charged particles in matter has been derived by Bethe¹), and is extensively discussed by Fano²). For the present application to silicon, the following expression will be used^{3,4}):

$$S = (0.30706 z^2 / A \cdot \underline{\beta}^2) \{ Z [f(\underline{\beta}) - \ln I] - C_K - C_L \} \quad (1)$$

where

ze = charge of incident particle

$A = 28.086$ = chemical atomic weight of silicon

$\underline{\beta} = v/c$ = velocity of particle/velocity of light

$Z = 14$ = atomic number of silicon

$f(\underline{\beta}) = \ln[2 mc^2 \underline{\beta}^2 / (1 - \underline{\beta}^2)] - \underline{\beta}^2$

$I = 173.5$ eV = mean ionization potential of Si (ref. 11)

C_K = Walske's K-shell correction⁵)

C_L = Walske's L-shell correction⁶), modified to fit experimental data^{7,8})

$\underline{\beta}^2 = \underline{\zeta}(\underline{\zeta}+2)/(\underline{\zeta}+1)^2$ where $\underline{\zeta} = E/Mc^2$

E = kinetic energy of particle of restmass M .

For a discussion of the effective charge at low velocities, see ref. 3 or 4.

The ranges R in the continuous slowing down approximation²) (csda) are calculated from S :

$$R = \int_{1 \text{ MeV}}^E (1/S)dE + R(1 \text{ MeV}). \quad (2)$$

2.2. Applications to experiments

A number of relatively small corrections should be considered for the use in experiments of S and R as defined above.

The distribution functions in energy E observed after a beam of particles has traversed a foil ("straggling distributions") are asymmetric, especially for small energy losses^{9,10}), but even for a final energy of $E_1 \sim 0.2 E$, a straggling asymmetry is still found^{11,34}). In addition, an asymmetry is caused by multiple scattering^{7,11}). It gets larger with thicker absorbers. A detailed discussion is given in Ref. 12. The multiple scattering correction for total ranges can be obtained from fig. 1.

At particle energies in excess of a few MeV, nuclear reactions will cause a perceptible attenuation of the beam intensity^{3,13,14}). A rough estimate can be obtained with the following equation

$$\frac{I}{I_0} = e^{-\Delta/L} \quad (3)$$

where I/I_0 is the fraction of the beam transmitted through an absorber of thickness Δ and the mean free path length is given for protons by

$$L \sim 31 \cdot A^{1/3} \text{ g cm}^{-2} \quad (4)$$

For particle identification applications, these effects are usually small and can be partially avoided by the use of more sophisticated instrumentation (systems with three or more counters, anticoincidence arrangements etc).

The Lewis correction¹⁵), the difference between the actual path-length and the csda range, is usually less than 0.1% for protons and heavier particles.

2.3. Stopping-power and range tables

While accurate energy-loss measurements¹¹) in silicon are available for protons with energies between 3 and 30 MeV, the determination of the parameters at low energies leans heavily on the data for aluminum^{7,8}). It has been assumed that eq. (1) applies equally well to Al and Si, in particular that the L-shell correction can be scaled using Walske's η_L .

For the starting ranges R (1 MeV), measured values are available for protons⁷), tritons¹⁶) and α particles^{17,18}) in aluminum. The following procedure was used to get starting ranges for the other particles: ranges were calculated for particles from 0.25 to 1 MeV. The ratio of measured to calculated range was then used for the other particles. Errors of at least $\pm 0.2 \text{ mg cm}^{-2}$ should be assigned to the starting ranges. The starting ranges for Si were assumed to be 0.981 of the Al values. The accurate energy-loss measurements for heavy ions in Al of ref. (19) are not suitable to give starting values for the ranges. Further measurements would be highly desirable.

The charge-state corrections are not well-known for Li⁷ ions, and therefore the tables will be accurate only to a few percent below about 5 MeV.

The stopping power S for p, d, t, He³, He⁴ and Li⁷ ions in silicon is given in Table 1. The csda ranges R for the same ions are given in Table 2. For both tables, linear interpolation will give an

accuracy of 0.1%. Since the tables are a direct printout of computer output, it was not practical to change the number of digits presented, and this number is not to be considered indicative of the accuracy of the tables. An I-value of 173.5 eV was used for the calculation¹¹).

2.4. Comparison with experimental data

The silicon range curve for protons deviates by less than 0.2% from the experimental data of ref. (11) for the energy range from 3 to 30 MeV. An older measurement²⁰) gives an absorber thickness of 0.985 mg cm^{-2} of Si to be equivalent to 1.00 mg cm^{-2} of Al for 8-MeV deuterons. Nothing is said about the composition of the samples or the assumed density. From Table 2, the corresponding number is about 0.979, depending on what lower energy is used. See Ref. 33 for stopping power measurements.

To get a fair estimate of the overall accuracy, the following data should be considered, based on a calculation of Al ranges and stopping power with $I = 166 \text{ eV}$ (from ref. (11)).

It was found²¹) that there exists a difference of up to 1% between the proton energy-loss measurements of ref. (11) and the stopping-power measurements of ref. (8). No explanation for this difference has been forwarded so far.

For the α -particle ranges there is a systematic deviation of between 3 and 7% from the experimental data of ref. (17), and about 3% from ref. (18). Since $I = 166 \text{ eV}$ was used for Al, these deviations are not unexpected. The triton ranges of ref. (16) agree to about 1% with Table 2.

Burkig and MacKenzie's range measurement²²) at 18.00 MeV agrees to 0.05 mg cm^{-2} with the Al range table. The Princeton range data⁷) agree with the table to 0.3% above 3.5 MeV.

It should be pointed out that the shell corrections used here do not appear to decrease fast enough for Al data (see fig. 4 of ref. (23)). A shift of the peak of the K-shell correction to lower energies might improve the situation somewhat.

2.5. Practical use of the tables

A list comparing thickness of silicon in different units is given in Table 3.

Monoenergetic particles of initial kinetic energy E will emerge from an absorber of thickness Δ with a mean energy $\langle E_1 \rangle$ given by

$$\Delta = \int_{\langle E_1 \rangle}^E (1/S)dE . \quad (5)$$

For most practical purposes, a csda-range table giving R as a function of E can be used to determine $\langle E_1 \rangle$: first, the mean residual range $R(\langle E_1 \rangle)$ is determined from

$$R(\langle E_1 \rangle) = R(E) - \Delta$$

and $\langle E_1 \rangle$ is obtained by interpolation from the table.

In applications using computers this method requires table look up. This is simple if the argument (here the energy E) shows a regular spacing, permitting selection of necessary locations with integer algebra. See Table 4 for an example.

If the energy difference $E - \langle E_1 \rangle$ is small enough, the mean value theorem can be used and

$$E - \langle E_1 \rangle = \underline{\Delta} \cdot S(E') \quad (6)$$

where $S(E')$ is the stopping power at an energy $E' \sim (E + \langle E_1 \rangle)/2$. This method requires successive approximations and thus is not very suitable for practical applications.

A third method is useful if an approximation formula is given for the stopping power and the range (see Table 5):

$$S = C \cdot E^{\underline{\alpha}} \quad (7)$$

$$\underline{\Delta} R = C_R (E^{\underline{\beta}} - E_1^{\underline{\beta}}) \quad (8)$$

where $\underline{\beta} = 1 - \underline{\alpha}$ and $C_R = 1/(C \cdot \underline{\beta})$. The mean residual energy then is obtained analytically:

$$\langle E_1 \rangle = (E^{\underline{\beta}} - \underline{\Delta}/C_R)^{1/\underline{\beta}} \quad (9)$$

If a digital computer is used to analyze pulses from an identifier system giving pulseheights in discrete channels proportional to the particle energy, it will be useful to generate range tables for energies corresponding to the value of the energy for the center of each channel. The residual range RX for a particle having a total energy producing a pulse in channel J then is simply $RX(J)$.

3. Useful Data for Particle-Identifier Applications

Many articles describing analog-particle identifiers based on the use of eqs. (7) and (8) have appeared (e.g. refs. (25 and 26)). In order to achieve a better understanding of the approximations involved, the following functions derived from Tables 1 and 2 are given here:

- a) The quantity $q = R/E^{1.76}$ is plotted in fig. 2.
- b) The quantity $\gamma = \frac{\ln[R(E)/0.763 \cdot R(1 \text{ MeV})]}{\ln E}$ is plotted in fig. 3.
- c) The values C , α and $C_R = \text{CRL}$ evaluated from eq. (7) are given in Table 5 for energy intervals from $E_1 = \text{LOWER } E$ to $E_2 = \text{UPPER } E$ such that the maximum deviation from Table 1 does not exceed about 0.1, 0.3, 0.6 or 1%. The actual deviation at the center point of the tabular entries is given in % under MAX.DEV.
- d) Since the resolution of an identifier systems depends on the ratio of the straggling width σ to the mean energy loss, the quantity $\zeta = \sigma/(E - \langle E_1 \rangle)$ is plotted versus E_1/E for protons of initial energies $E = 10, 30$ and 100 MeV in fig. 4.
- e) For the particle pairs (d,p) , (t,d) , (He^3,t) and $(\text{He}^4,\text{He}^3)$ the ratio r of their energy losses $r = (E - \langle E_1 \rangle)_x/(E - \langle E_1 \rangle)_y$ is plotted as a function of E for detectors of thicknesses $\Delta = 20 \text{ mg cm}^{-2}$, $\Delta = 50 \text{ mg cm}^{-2}$, in fig. 5 and for $\Delta = 100 \text{ mg cm}^{-2}$ and $\Delta = 500 \text{ mg cm}^{-2}$ in fig. 6
- f) The "particle characteristic" $E^{1.76} - \langle E_1 \rangle^{1.76}$ (fig. 2a of ref. (26)) is given by a suitable average of q of fig. 2 over the range $\langle E_1 \rangle$ to E .
- g) The relative stopping power of Al (based on $I = 166 \text{ eV}$) and Si is given in fig. 7.

4. Some Comments about Energy Measurements in Silicon Detectors

A number of details have to be considered if an energy determination in silicon detectors is desired to an accuracy of better than 1%.

Obviously, corrections have to be applied for the energy loss in the entrance window. A practical way to determine its thickness is to measure the change in pulseheight of natural α particles as a function of the angle of incidence of the particles.

The energy ϵ for the formation of an electron hole pair increases for particles of low velocities. For more energetic particles this effect can be lumped together into an ionization defect. This means that particles will seem to deposit less energy than they actually possess. An estimate of the effect²⁷⁾ indicates that the observed energy will have to be increased by about $6 \cdot M$ keV where M is the particle mass in amu. The effect is not easy to determine because it is obscured by losses due to incomplete charge collection and other effects²⁸⁾). Contradictory results are obtained by Siffert et al²⁹⁾ and by Ewing³⁰⁾.

For protons of energies from 3 to 18 MeV, pulseheight and energy in a 2-mm Li-drift-silicon detector were observed to be proportional to better than ± 5 keV after correction for entrance window and ionization defect¹¹⁾. At 20 MeV in a 3-mm detector, the pulseheight was reduced by about 1% due to pulse rise time problems.

A definite dependence of ϵ on temperature and also a difference in ϵ for electrons and α particles has been found³¹⁾). A difference in ϵ for protons and α particles has been observed at the University of

Southern California by the authors, but further experimentation will be necessary to test all possible sources of systematic error.

An extensive discussion of counter resolution and associated problems is given in ref. (32).

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List of Tables

1. Stopping power S of p , d , t , He^3 , α and Li^7 ions in silicon.
2. Ranges R in silicon.
3. Conversion table for different units of thickness for single crystal silicon.
4. Example of Table lookup in FORTRAN IV.
5. The coefficients C , α , and C_R for approximate calculation of stopping power and ranges (see p. 8).

Figure Captions

1. Multiple scattering correction for mean ranges of protons in Si. An observed projected median range (corrected for nuclear absorption) has to be increased by ΔR to give mean range.
2. The quotient $q = R/E^{1.76}$ for six particles. Note the strong dependence of q on the value of γ for protons: for $\gamma = 1.76$, q changes by $\pm 1\%$ from 6.5 to 65 MeV, while for $\gamma = 1.72$, the same change occurs between 3.2 and 18 MeV.
3. The exponent γ in the approximate expression $R(E) = C_R \cdot E^\gamma$ where C_R is a constant chosen to be $R(1 \text{ MeV}) \cdot 0.763$. This produces $\gamma = 1.76$ at about 40 MeV for protons and gives approximately the smallest change in γ for protons from about 7 to 200 MeV.
4. The straggling parameter α as a function of the mean energy loss $\Delta E = E - \langle E_1 \rangle$. Plotted is the fraction $\alpha/\Delta E$ versus the residual energy $\langle E_1 \rangle$ expressed as a fraction of the initial energy for $E = 10 \text{ MeV}$ and $E = 100 \text{ MeV}$.

Figure Captions (cont'd)

5 + 6. The ratio r of the energy loss of two particles x, y in different thicknesses of silicon absorbers: $r = (E - \langle E_1 \rangle)_x / (E - \langle E_1 \rangle)_y$.

7. Relative stopping power of Si and Al. Plotted is

$$S_r = (S_{Si}/S_{Al}) - 1 \text{ in percent for 5 particles.}$$

STOPPING POWER IN MEV.SQCM/GM FOR SILICON

Z = 14 A = 28.086 I = 173.5

E(MEV)	P	D	T	HE 3	HE 4	LI 7	E(MEV)	P	D	T	HE 3	HE 4	LI 7
75.00	7.226	12.325	16.923	67.680	84.520	294.158	120.00	5.120	8.559	11.704	46.808	58.436	204.250
76.00	7.155	12.198	16.747	66.980	83.648	291.174	122.00	5.061	8.451	11.554	46.208	57.683	201.628
77.00	7.085	12.074	16.576	66.295	82.795	288.257	124.00	5.003	8.367	11.408	45.625	56.951	199.081
78.00	7.016	11.953	16.409	65.627	81.962	285.405	126.00	4.947	8.245	11.266	45.058	56.240	196.604
79.00	6.950	11.834	16.246	64.973	81.148	282.614	128.00	4.893	8.147	11.129	44.508	55.548	194.196
80.00	6.885	11.718	16.086	64.334	80.352	279.884	130.00	4.840	8.051	10.995	43.974	54.877	191.853
81.00	6.821	11.605	15.930	63.709	79.573	277.212	132.00	4.789	7.958	10.865	43.454	54.223	189.572
82.00	6.759	11.495	15.777	63.098	78.811	274.596	134.00	4.739	7.867	10.738	42.948	53.587	187.351
83.00	6.698	11.386	15.627	62.500	78.065	272.034	136.00	4.690	7.779	10.615	42.455	52.968	185.189
84.00	6.638	11.280	15.481	61.914	77.335	269.529	138.00	4.643	7.694	10.496	41.976	52.366	183.082
85.00	6.580	11.177	15.338	61.341	76.620	267.076	140.00	4.597	7.610	10.379	41.509	51.778	181.029
86.00	6.523	11.075	15.197	60.780	75.920	264.671	142.00	4.552	7.529	10.265	41.054	51.206	179.027
87.00	6.467	10.976	15.060	60.230	75.234	262.315	144.00	4.509	7.450	10.154	40.611	50.648	177.073
88.00	6.413	10.879	14.925	59.692	74.561	260.004	146.00	4.467	7.372	10.046	40.178	50.104	175.167
89.00	6.359	10.783	14.793	59.164	73.903	257.739	148.00	4.425	7.297	9.941	39.757	49.573	173.307
90.00	6.307	10.690	14.664	58.647	73.257	255.517	150.00	4.385	7.224	9.838	39.345	49.055	171.491
91.00	6.256	10.598	14.537	58.141	72.624	253.337	152.00	4.346	7.152	9.738	38.946	48.549	169.717
92.00	6.206	10.509	14.413	57.644	72.003	251.199	154.00	4.308	7.082	9.640	38.554	48.055	167.984
93.00	6.157	10.421	14.291	57.156	71.394	249.101	156.00	4.270	7.014	9.544	38.171	47.573	166.290
94.00	6.108	10.334	14.172	56.678	70.796	247.041	158.00	4.234	6.947	9.451	37.797	47.101	164.634
95.00	6.061	10.250	14.054	56.209	70.210	245.019	160.00	4.198	6.882	9.359	37.432	46.641	163.016
96.00	6.015	10.167	13.939	55.749	69.635	243.035	162.00	4.164	6.818	9.270	37.075	46.190	161.432
97.00	5.969	10.085	13.826	55.297	69.070	241.088	164.00	4.130	6.756	9.183	36.726	45.750	159.883
98.00	5.925	10.005	13.715	54.854	68.516	239.175	166.00	4.097	6.695	9.097	36.384	45.319	158.368
99.00	5.881	9.927	13.607	54.419	67.971	237.296	168.00	4.064	6.636	9.014	36.050	44.897	156.884
100.00	5.838	9.850	13.500	53.991	67.437	235.449	170.00	4.033	6.578	8.932	35.723	44.485	155.432
101.00	5.796	9.774	13.395	53.572	66.912	233.634	172.00	4.002	6.521	8.852	35.403	44.081	154.010
102.00	5.754	9.701	13.292	53.159	66.396	231.851	174.00	3.971	6.465	8.774	35.090	43.686	152.618
103.00	5.714	9.628	13.190	52.754	65.889	230.097	176.00	3.942	6.411	8.697	34.783	43.299	151.254
104.00	5.674	9.556	13.091	52.356	65.390	228.373	178.00	3.913	6.357	8.622	34.483	42.919	149.917
105.00	5.635	9.486	12.993	51.965	64.901	226.677	180.00	3.884	6.305	8.548	34.189	42.548	148.607
106.00	5.596	9.416	12.897	51.580	64.419	225.010	182.00	3.857	6.254	8.476	33.901	42.183	147.322
107.00	5.558	9.348	12.802	51.202	63.945	223.369	184.00	3.829	6.203	8.406	33.618	41.826	146.062
108.00	5.521	9.282	12.709	50.830	63.480	221.755	186.00	3.803	6.154	8.337	33.341	41.476	144.827
109.00	5.485	9.216	12.618	50.465	63.022	220.167	188.00	3.777	6.106	8.269	33.070	41.133	143.615
110.00	5.449	9.151	12.528	50.105	62.571	218.604	190.00	3.751	6.059	8.202	32.804	40.797	142.425
111.00	5.413	9.087	12.440	49.751	62.128	217.066	192.00	3.726	6.012	8.137	32.542	40.466	141.258
112.00	5.379	9.025	12.353	49.403	61.691	215.553	194.00	3.701	5.967	8.073	32.286	40.142	140.113
113.00	5.344	8.963	12.267	49.061	61.262	214.064	196.00	3.677	5.922	8.010	32.035	39.824	138.988
114.00	5.311	8.903	12.183	48.724	60.839	212.597	198.00	3.654	5.879	7.948	31.788	39.512	137.884
115.00	5.278	8.843	12.100	48.392	60.423	211.153	200.00	3.631	5.836	7.888	31.546	39.206	136.799
116.00	5.245	8.785	12.018	48.065	60.014	209.731							
117.00	5.213	8.727	11.938	47.744	59.610	208.330							
118.00	5.182	8.670	11.858	47.427	59.213	206.950							
119.00	5.151	8.614	11.781	47.115	58.822	205.590							
120.00	5.120	8.559	11.704	46.808	58.436	204.250							

Table 3

Conversion table for thickness of monocrystalline silicon absorbers. Density used $\rho = 2.3290 \text{ g cm}^{-3}$ (Ref. 24)

mg cm^{-2}	mm	μ	mils = 0.001"
1	0.0043	4.294	0.169
2	0.0086	8.587	0.338
3	0.0129	12.881	0.507
4	0.0172	17.175	0.676
5	0.0215	21.468	0.845
6	0.0258	25.76	1.014
7	0.0301	30.06	1.183
8	0.0344	34.35	1.352
9	0.0386	38.64	1.521
10	0.0429	42.94	1.690
20	0.0859	85.87	3.338
40	0.1718	171.75	6.762
70	0.3006	300.6	11.83
100	0.4294	429.4	16.90
200	0.8587	858.7	33.38
400	1.7175	1717.5	67.62
700	3.006	3006.	118.3
1000	4.294	4294	169.0
2000	8.587	8587	333.8
4000	17.175	17175	676.2
7000	30.056	30056	1183
10000	42.9369	42937	1690.431

Table 4

Table lookup in a FORTRAN program.

Example: Find the range RX for a particle of energy El = 2.12. The following FORTRAN statements are necessary:

DIMENSION R(11)

.

.

.

XA = El*5.0

JX = XA - 3.99999

RX = R(JX) + (R(JX+1) - R(JX))*(XA - FLOAT(JX+4))

.

.

.

J	E	R(J)
1	1.0	3.80
2	1.2	5.01
3	1.4	6.36
4	1.6	7.83
5	1.8	9.43
6	2.0	11.15
7	2.2	13.00
8	2.4	14.96
9	2.6	17.04
10	2.8	19.24
11	3.0	21.55

Note that it is not necessary to store E in the memory.

Table 5.

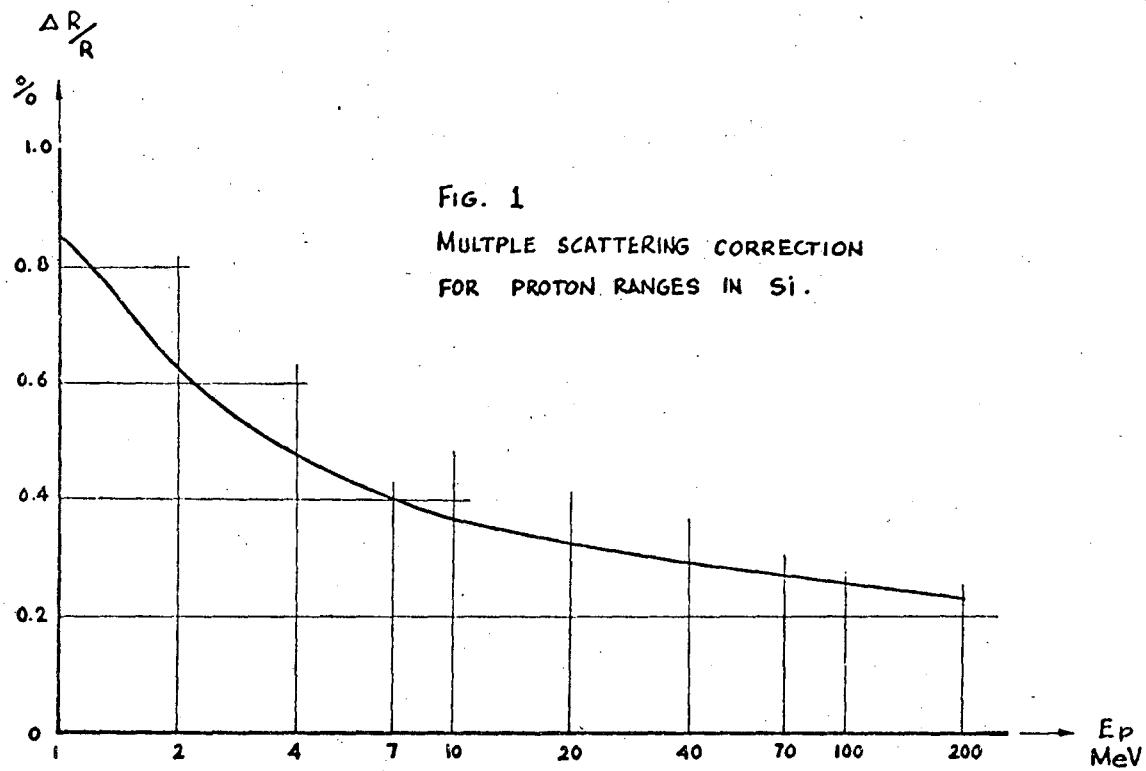
POLYNOMIAL APPROXIMATION FOR SILICON							STOPPING POWER S=C*E**ALPHA, RANGE R=CRL*E** $(1-\text{ALPHA})$.								
PARTICLE	P	LOWER E	UPPER E	ALPHA	C	MAX. DEV	CRL	PARTICLE	D	LOWER E	UPPER E	ALPHA	C	MAX. DEV	CRL
ERROR=	.1	0/0						ERROR=	.1	0/0					
1.000	1.300	-617930	174.902	-1056	3.53470E-03			1.000	1.300	-520459	256.298	-1304	2.56614E-03		
1.300	1.800	-652180	176.499	-1428	3.42925E-03			1.300	1.700	-559184	258.916	-1271	2.47710E-03		
1.800	2.500	-683931	179.824	-1110	3.30238E-03			1.700	2.200	-596165	264.047	-1101	2.37269E-03		
2.500	3.600	-710193	184.204	-1102	3.17435E-03			2.200	2.900	-630300	271.249	-1145	2.26133E-03		
3.600	5.400	-732328	189.502	-1024	3.04619E-03			2.900	3.900	-662246	280.634	-1123	2.14370E-03		
5.400	8.600	-752515	196.064	-1058	2.91032E-03			3.900	5.400	-690440	291.612	-1046	2.02859E-03		
8.600	14.600	-770541	203.818	-1041	2.77109E-03			5.400	7.800	-715280	304.087	-1039	1.91720E-03		
14.600	52.000	-782407	210.407	-1108	2.66645E-03			7.800	11.600	-736314	317.513	-1059	1.81388E-03		
52.000	77.000	-763266	195.080	-1079	2.90716E-03			11.600	18.500	-755371	332.696	-1036	1.71231E-03		
77.000	105.000	-738363	175.079	-1056	3.28568E-03			18.500	32.000	-773005	350.262	-1040	1.61027E-03		
105.000	138.000	-708246	152.182	-1061	3.84669E-03			32.000	105.000	-782572	362.071	-1040	1.54939E-03		
138.000	174.000	-674162	128.655	-1015	4.64277E-03			105.000	156.000	-762592	329.920	-1052	1.71965E-03		
174.000	200.000	-643992	110.111	-0427	5.52422E-03			156.000	200.000	-740027	294.389	-0664	1.95219E-03		
ERROR=	.3	0/0						ERROR=	.3	0/0					
1.000	1.600	-630049	174.902	-3279	3.50755E-03			1.000	1.600	-535653	256.298	-3978	2.54075E-03		
1.600	2.800	-683155	179.323	-3237	3.31315E-03			1.600	2.500	-600379	264.215	-3276	2.36494E-03		
2.800	5.600	-726342	187.476	-3255	3.08978E-03			2.500	4.200	-657904	278.515	-3511	2.16566E-03		
5.600	12.800	-760621	198.881	-3015	2.85588E-03			4.200	7.800	-706393	298.586	-3203	1.96269E-03		
12.800	67.000	-779611	208.747	-3147	2.69187E-03			7.800	16.500	-744207	322.703	-3107	1.77664E-03		
67.000	114.000	-740052	176.759	-3004	3.25129E-03			16.500	47.500	-775741	352.530	-3024	1.59744E-03		
114.000	174.000	-687374	137.730	-3116	4.30289E-03			47.500	132.000	-778857	356.796	-3157	1.57557E-03		
174.000	200.000	-643992	110.111	-0427	5.52422E-03			132.000	200.000	-746440	304.563	-1683	1.88005E-03		
ERROR=	.6	0/0						ERROR=	.6	0/0					
1.000	2.000	-642434	174.902	-6535	3.48110E-03			1.000	1.800	-544203	256.298	-6060	2.52668E-03		
2.000	4.800	-710855	183.397	-6105	3.18709E-03			1.800	3.500	-628601	269.333	-6419	2.27979E-03		
4.800	16.500	-761745	198.637	-6279	2.85757E-03			3.500	8.000	-700179	294.600	-6140	1.99651E-03		
16.500	78.000	-777539	207.630	-6003	2.70951E-03			8.000	24.000	-752361	328.366	-6181	1.73787E-03		
78.000	152.000	-717962	160.164	-6016	3.63432E-03			24.000	164.000	-776683	354.755	-6037	1.58658E-03		
152.000	200.000	-655272	116.892	-1570	5.16829E-03			164.000	200.000	-737936	291.146	-0436	1.97631E-03		
ERROR=	1.0	0/0						ERROR=	1.0	0/0					
1.000	2.500	-653642	174.902	-1.0302	3.45751E-03			1.000	2.200	-558391	256.298	-1.0630	2.50367E-03		
2.500	9.000	-734429	188.341	-1.0160	3.06126E-03			2.200	5.400	-662635	278.254	-1.0051	2.16153E-03		
9.000	100.000	-772518	204.781	1.0102	2.75499E-03			5.400	20.500	-739485	316.757	-1.0267	1.81490E-03		
100.000	200.000	-685216	136.989	.8409	4.33169E-03			20.500	198.000	-773088	350.593	1.0250	1.60867E-03		
								198.000	200.000	-729303	278.128	.0001	2.07914E-03		

POLYNOMIAL APPROXIMATION FOR SILICON

PARTICLE	T	LOWER E	UPPER E	ALPHA	C	MAX. DEV	CRL
ERROR= .1 0/0							
	1.000	1.200	-401724	302.610	-1043	2.35751E-03	
	1.200	1.400	-385125	301.695	.3223	2.39300E-03	
	1.400	1.800	-510147	314.657	-1099	2.10447E-03	
	1.800	2.300	-545983	321.356	-1061	2.01284E-03	
	2.300	3.000	-582705	331.337	-1226	1.90691E-03	
	3.000	3.900	-617808	344.364	-1053	1.79496E-03	
	3.900	5.200	-650374	359.970	-1126	1.68326E-03	
	5.200	7.200	-680768	378.468	-1130	1.57204E-03	
	7.200	10.200	-706990	398.575	-1052	1.46980E-03	
	10.200	15.500	-729743	420.202	-1105	1.37581E-03	
	15.500	24.500	-750656	444.992	-1019	1.28365E-03	
	24.500	40.500	-768623	471.315	-1013	1.19965E-03	
	40.500	168.000	-781536	494.388	-1047	1.13537E-03	
	168.000	200.000	-765477	455.335	.0202	1.24396E-03	
ERROR= .3 0/0							
	1.000	1.600	-424745	302.610	-4142	2.31942E-03	
	1.600	2.500	-543431	319.970	-3545	2.02490E-03	
	2.500	3.900	-605842	338.802	-3180	1.83803E-03	
	3.900	6.400	-661029	365.228	-3122	1.64838E-03	
	6.400	11.800	-707354	398.025	-3100	1.47152E-03	
	11.800	25.000	-744697	436.453	-3124	1.31324E-03	
	25.000	67.000	-775320	481.667	-3022	1.16944E-03	
	67.000	198.000	-779207	489.604	.3078	1.14797E-03	
	198.000	200.000	-760933	444.505	.0001	1.27756E-03	
ERROR= .6 0/0							
	1.000	1.700	-434884	302.610	-1.5424	2.30303E-03	
	1.700	3.100	-563387	323.964	-6248	1.97441E-03	
	3.100	6.000	-644674	355.171	-6008	1.71192E-03	
	6.000	14.800	-711824	400.581	-6041	1.45831E-03	
	14.800	52.000	-763084	459.916	-6142	1.23324E-03	
	52.000	200.000	-779926	491.562	.3468	1.14293E-03	
ERROR= 1.0 0/0							
	1.000	1.700	-434884	302.610	-1.5424	2.30303E-03	
	1.700	3.700	-575552	326.062	-1.0058	1.94656E-03	
	3.700	10.000	-677757	372.712	-1.0314	1.59918E-03	
	10.000	41.000	-750625	440.799	-1.0111	1.29588E-03	
	41.000	200.000	-779807	491.253	.2941	1.14373E-03	

STOPPING POWER S=C*E**ALPHA, RANGE R=CRL*E**(.1-ALPHA).

PARTICLE	HE	3	LOWER E	UPPER E	ALPHA	C	MAX. DEV	CRL
ERROR= .1 0/0								
	1.000	1.100	-239861	1183.209	-4695	6.81656E-04		
	1.100	1.600	-411304	1202.702	-4314	5.89144E-04		
	1.600	2.100	-530978	1272.290	-1386	5.13387E-04		
	2.100	2.700	-568649	1308.352	-1169	4.87248E-04		
	2.700	3.500	-604184	1355.355	-1151	4.59931E-04		
	3.500	4.600	-637166	1412.529	-1083	4.32424E-04		
	4.600	6.200	-668201	1481.037	-1096	4.04749E-04		
	6.200	8.600	-695216	1555.867	-1027	3.79142E-04		
	8.600	12.600	-719475	1639.238	-1045	3.54783E-04		
	12.600	19.000	-740286	1727.994	-1030	3.32535E-04		
	19.000	30.500	-758999	1825.876	-1068	3.11360E-04		
	30.500	54.000	-775868	1934.240	-1009	2.91125E-04		
	54.000	150.000	-783212	1991.737	.1023	2.81556E-04		
	150.000	200.000	-767962	1845.220	.0475	3.06534E-04		
ERROR= .3 0/0								
	1.000	1.100	-239861	1183.209	-4695	6.81656E-04		
	1.100	1.600	-411304	1202.702	-4314	5.89144E-04		
	1.600	2.500	-534360	1279.776	-3544	5.06257E-04		
	2.500	3.900	-605867	1355.090	-3180	4.59539E-04		
	3.900	6.400	-661048	1460.776	-3122	4.12130E-04		
	6.400	11.800	-707367	1591.933	-3100	3.67916E-04		
	11.800	25.000	-744705	1745.610	-3124	3.28345E-04		
	25.000	67.000	-775325	1926.423	-3022	2.92395E-04		
	67.000	198.000	-779203	1958.090	.3080	2.87040E-04		
	198.000	200.000	-760922	1777.660	.0001	3.19456E-04		
ERROR= .6 0/0								
	1.000	1.200	-308034	1183.209	-6477	6.46129E-04		
	1.200	1.700	-436239	1211.192	-7652	5.74858E-04		
	1.700	3.100	-563414	1295.747	-6247	4.93635E-04		
	3.100	6.000	-644696	1420.558	-6007	4.28012E-04		
	6.000	14.800	-711837	1602.156	-6040	3.64614E-04		
	14.800	52.000	-763090	1839.439	-6141	3.08347E-04		
	52.000	200.000	-779923	1965.937	.3470	2.85778E-04		
ERROR= 1.0 0/0								
	1.000	1.600	-376537	1183.209	-1.0545	6.13975E-04		
	1.600	3.500	-567343	1294.222	-1.0409	4.92977E-04		
	3.500	9.000	-670556	1472.868	-1.0123	4.06420E-04		
	9.000	34.500	-744729	1733.574	-1.0088	3.30620E-04		
	34.500	200.000	-779261	1959.052	.2116	2.86889E-04		



XBL 677-4253

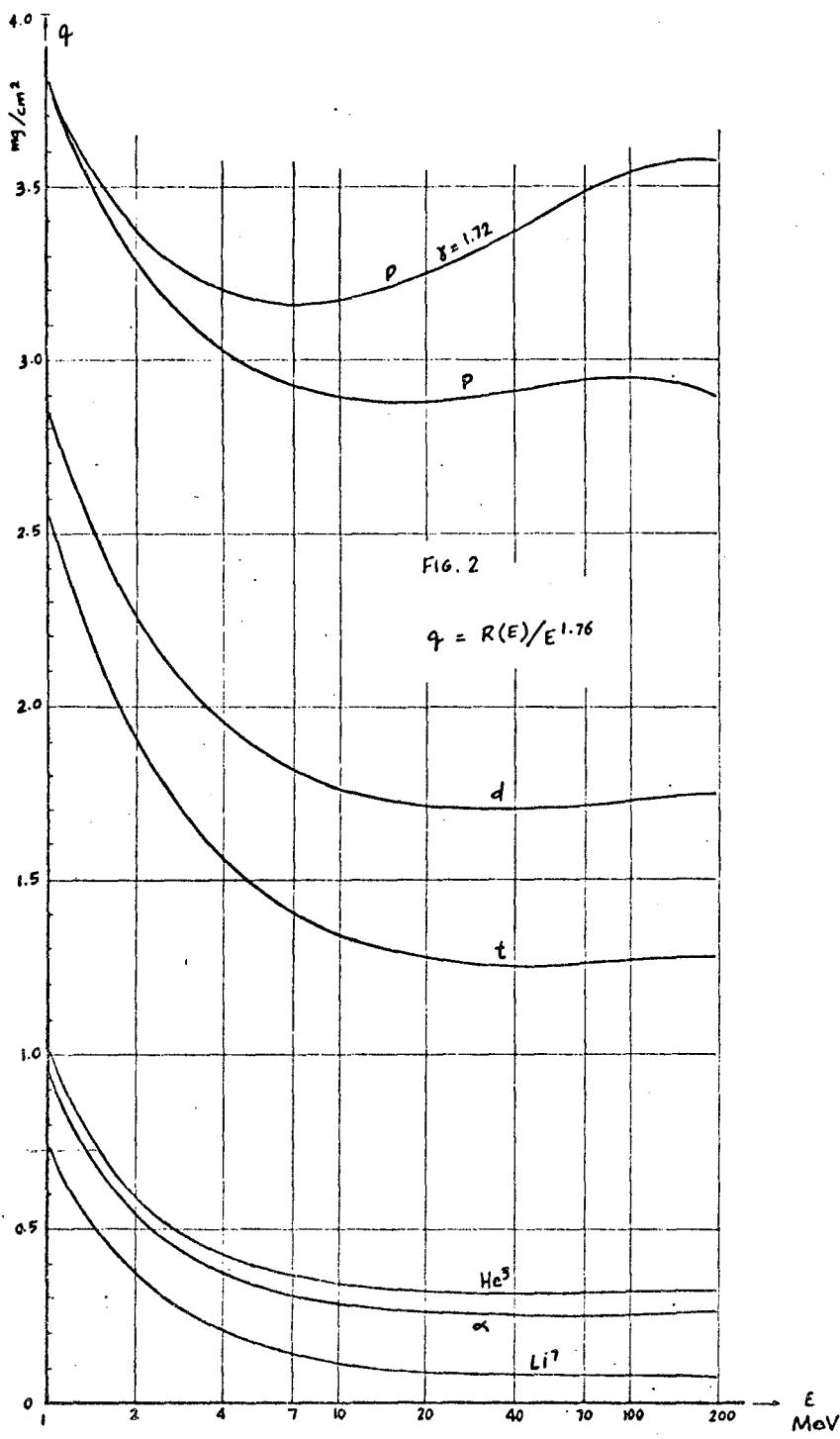
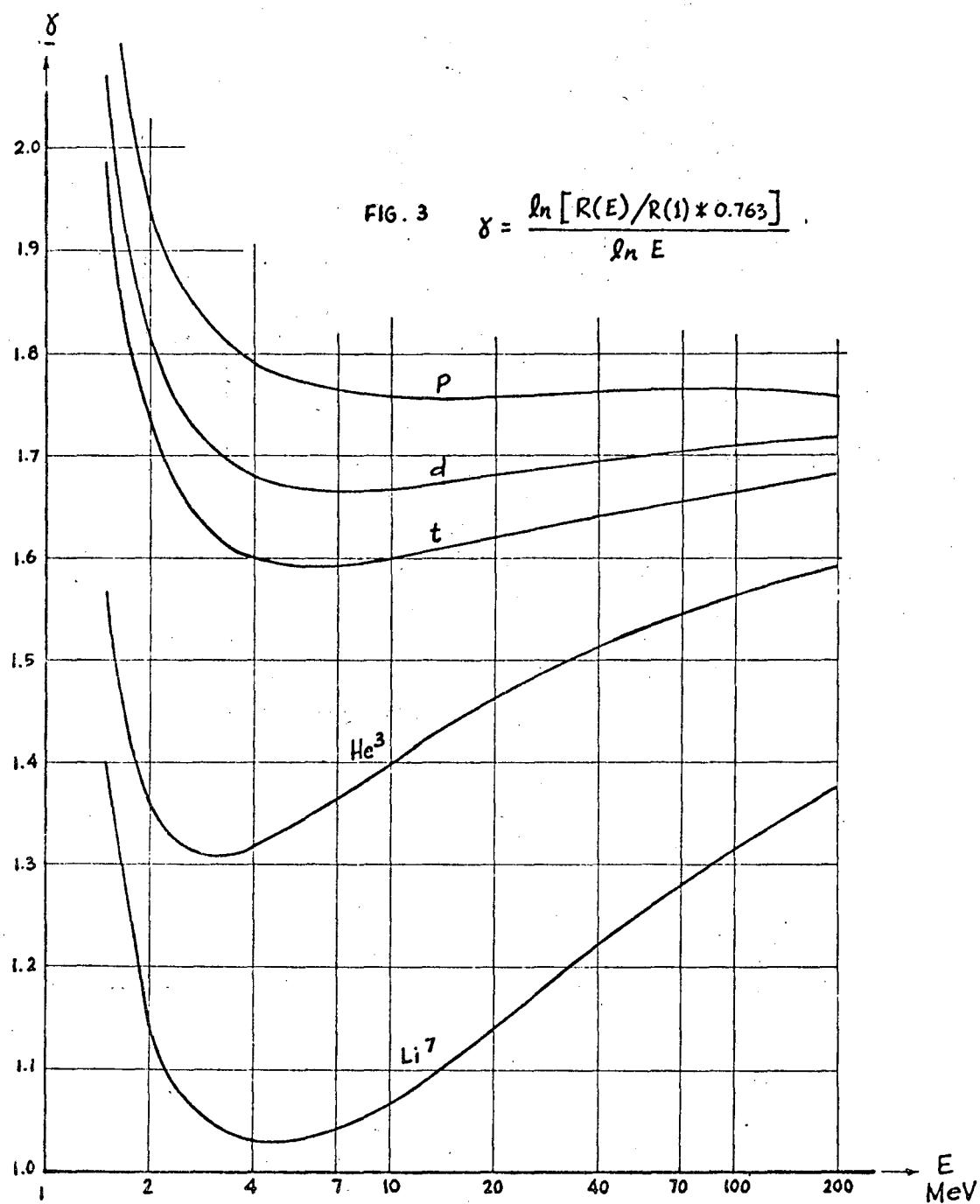
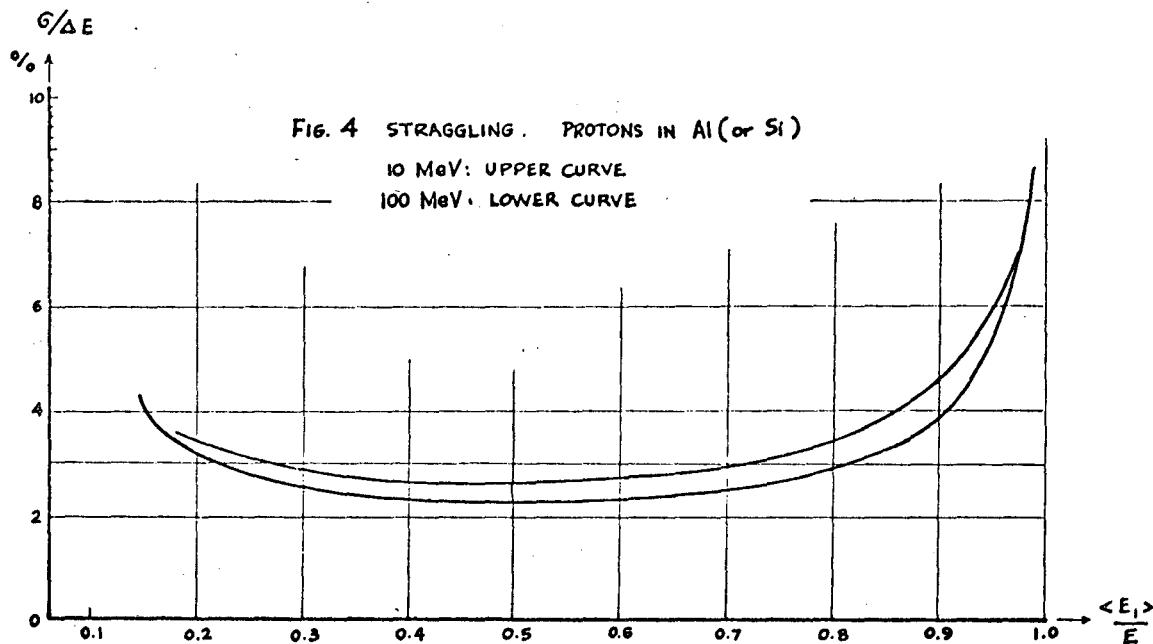


Fig. 2

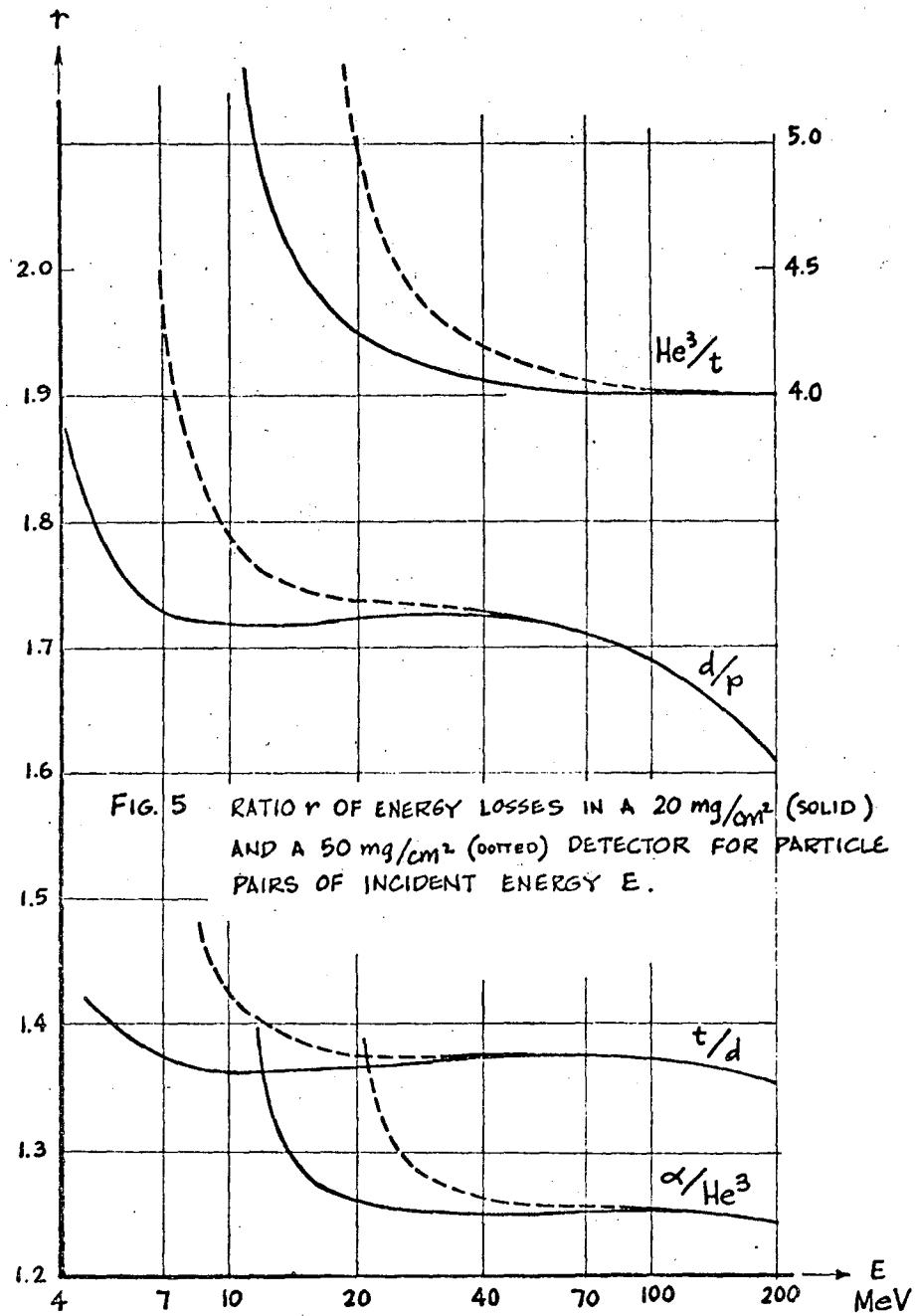
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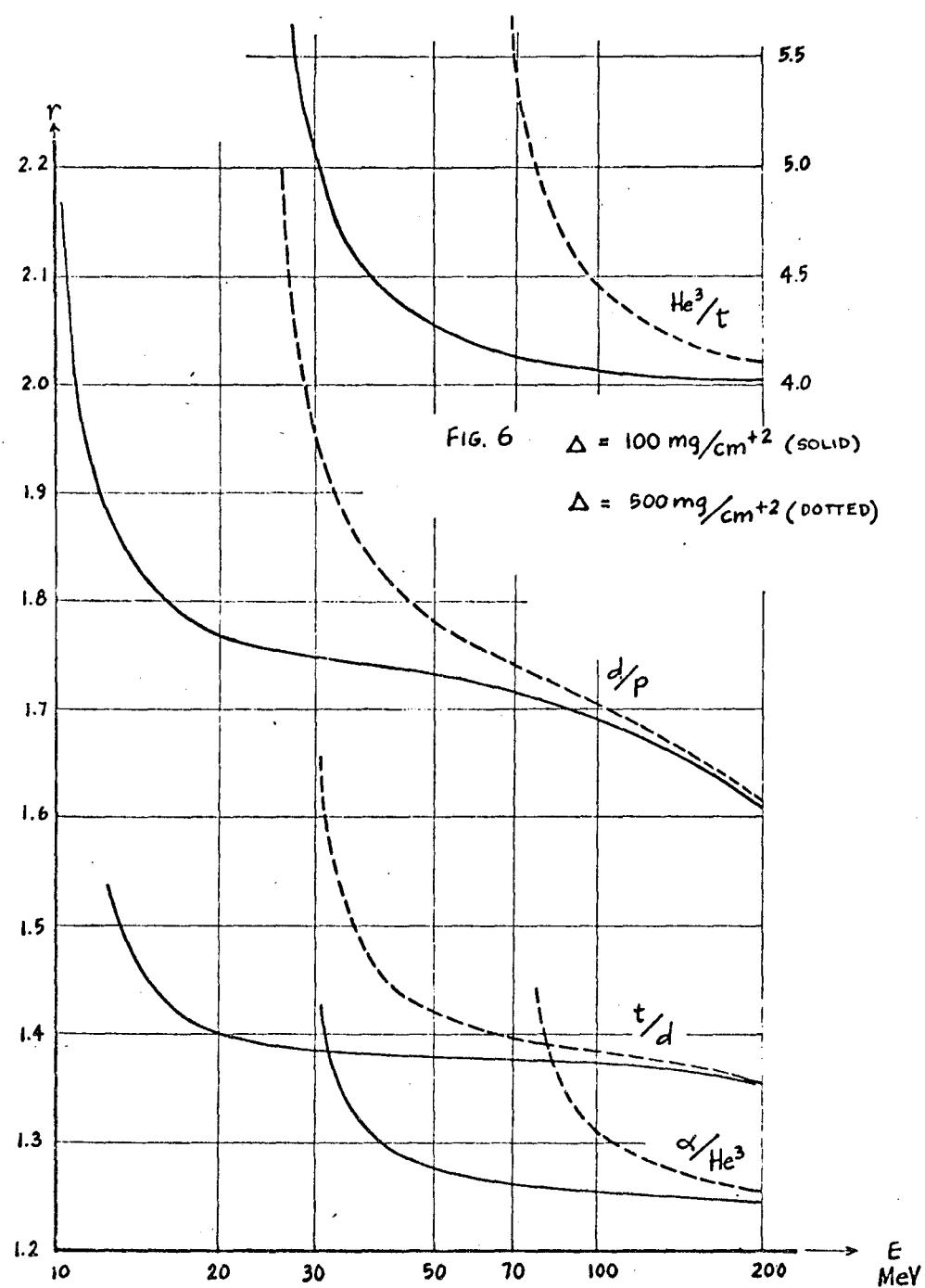
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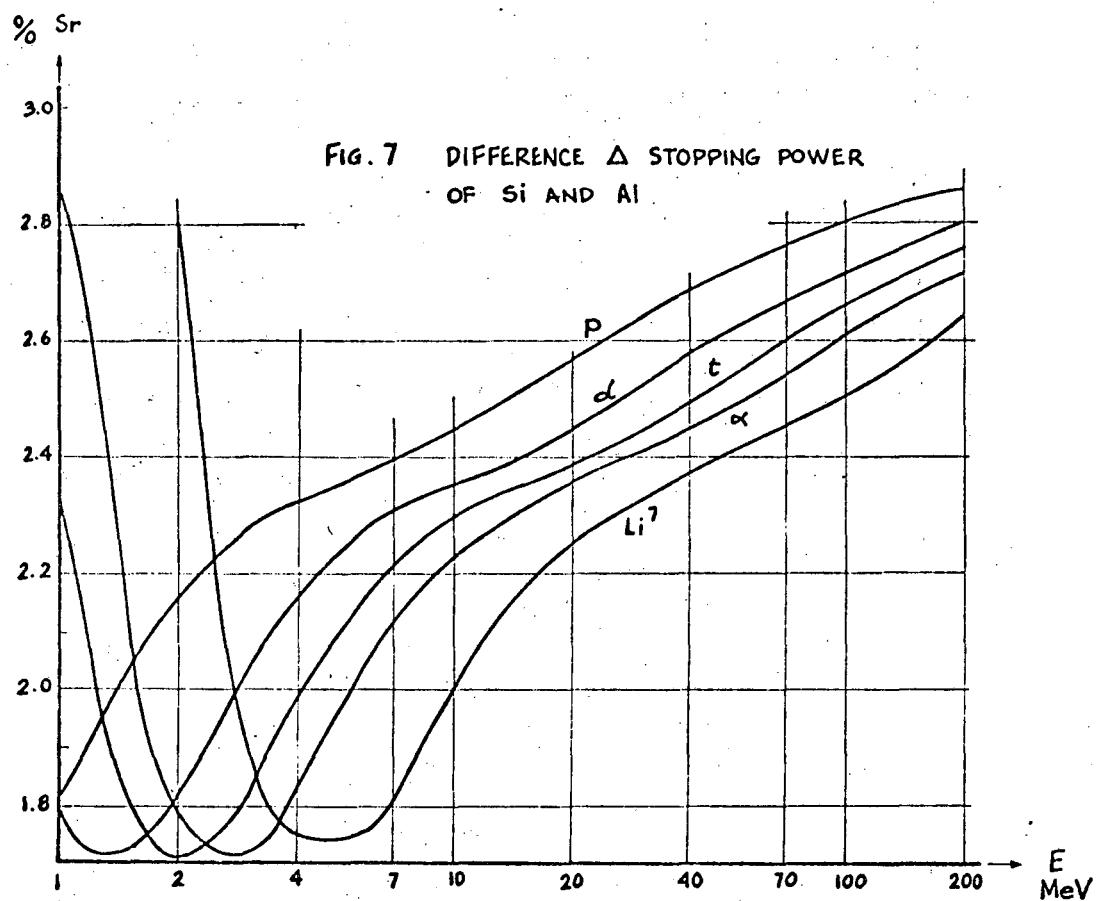
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